## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re A	Application of:	)	
N & A TZ (		:	Examiner: Unassigned
MAK	OTO HIGASHIKAWA ET AL.	) :	Group Art Unit: Not Yet Assigned
Applic	cation No.: Unassigned	)	
	on of Appln. No. 09/261,499	:	
	March 3, 1999	)	
		:	
Filed: Herewith		)	
		:	
For:	PROCESS FOR FORMING A	)	
	MICROCRYSTALLINE	:	
	SILICON SERIES THIN	)	
	FILM AND APPARATUS	:	
	SUITABLE FOR PRACTICING	)	
	SAID PROCESS	:	September 5, 2003
Comm	nissioner for Patents		
	Box 1450		

## <u>INFORMATION DISCLOSURE STATEMENT</u>

Sir:

Alexandria, VA 22313-1450

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed Form PTO-1449. Copies of the listed documents are of record in parent Application No. 09/261,499.

## CONCLUSION

It is respectfully requested that the above information be considered by the Examiner and that a copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

Applicants' undersigned attorney may be reached in our New York office by telephone at (212) 218-2100. All correspondence should continue to be directed to our address given below.

Respectfully submitted,

Attorney for Applicants
Registration No. 24947

FITZPATRICK, CELLA, HARPER & SCINTO 30 Rockefeller Plaza

New York, New York 10112-3801 Facsimile: (212) 218-2200

## FORM PTO 1449 (modified)

EXAMINER

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)

ATTY DOCKET NO.

00839.000419.1

APPLICATION NO. Div of Appln. No. 09/261,499

APPLICANT '

MAKOTO HIGASHIKAWA ET AL.

(555 551515. 5115515 1. 115555321.),			FILING DATE Here	FILING DATE Herewith		GROUPUnassigned	
			U.S. PATENT DOCUMENTS				
*EXAMINER INITIAL			NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	6065425	05/00	Takaki et al.	118	723		
	5652029	07/97	ltoh	427	569		
	5766696	06/98	ltoh	427	577		
	4400409	08/83	Izu et al.	427	39		
	5677236	10/97	Saitoh et al.	437	578		
	4492736	01/85	Tanner	427	578		
	4600801	07/86	Guha et al.	427	74		
	6100466	8/00	Nishimoto	427	588		
	5720826	02/98	Hayashi et al.	427	575		
	5362684	11/94	Saito et al.	427	575		
<del></del>			FOREIGN PATENT DOCUMENTS				
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
JF	9-256160	1997	Japan			Corresp. to USP 6,065,42	
JF	59-213176	1984	Japan			No	
JF	2575397	1997	Japan			No	
JF	57-195737	05/81	Japan			Eng. Abst.	
JF	59-212176	05/83	Japan			Eng. Abst.	
JF	3-6466	01/91	Japan			Abstract	
JF	57710	12/87	Japan			Abstract	
<del></del>		OTHER DOCUME	NT(S) (Including Author, Title, Date, Per	rtinent Pages, Etc.)			
	R. Flukiger, (VHR-GF for 844).	et al., "Prepar P-I-N Solar Ce	ation of Undoped and Dop lls, 23° IEEE Photovoltaic	ped Microcrystalline Specialists Confer	e Silicon ( nce, 199	μc-SiH) by 3 (pp. 839-	

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 1 of 2 Sheet 1 of 2

DATE CONSIDERED

FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			ATTY DOCKET NO.		APPLICATION NO. Division of Appl. 09/261,499			
			APPLICANTS'  MAKOTO HIGASHIKAWA ET AL.					
			FILING DATE  Herewith			GROUP Unassigned		
				S. PATENT DOCUMENTS				
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME		CLASS	SUBCLASS	FILING DATE
		4920917	05/90	Nakatani, et al.		128	718	
		6025039	02/00	Yajima		427	573	
		4585537	04/86	Nakayama, et al.		204	192	
					<u> </u>			
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<u> </u>	FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY		CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
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OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)								
EXAMINER DATE CONSIDERED								

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